

### Amendments to the Specification:

Please replace the paragraph starting on p. 4, line 9, with the following amended paragraph:

Fluid in the form of vapor and liquid is transported, with the use of heat, between reservoir 12, chamber 11 and trenches 22 used for optical switching. Arrows 13, arrows 14 and arrows 15 represent the application and removal of heat at various locations to facilitate transport of fluid in the system.

Please replace the paragraph starting on p. 4, line 13, with the following amended paragraph:

Heat is added to reservoir 12 so that vapor will be transported from reservoir 12 through conduit 19 to chamber 11. After the vapor enters chamber 11 through the filaments, the vapor begins to condense. Various structures within chamber 11 are used to achieve gettering of impurities in the system.

Please replace the paragraph starting on p. 8, line 19, with the following amended paragraph:

FIG. 7 illustrates suspended pillars of silicon suspending resistors within filaments, such as filaments 21 shown in FIG. 1. Looking down through a filament hole 121 are seen a silicon pillar 122, a silicon pillar 123 and a silicon pillar 124. Each of silicon pillars 122 through 124 is used to suspend a resistor within the filament hole 121. For example, each of silicon pillars 122 through 124 is covered with a layer of Pt placed over a layer of Ti or is covered with a layer of Pt placed between two layers of Ti. Ti/Pt resistors are designed to getter hydrocarbons. Ti/Pt covered resistors are designed to getter oxygen and water vapor.

Please replace the paragraph starting on p. 10, line 17, with the following amended paragraph:

Once initial cleaning of the device has been performed and initial testing has been passed, test structures such as those formed by conductors 50 and 54, and conductors 60 and 64 can be used for periodic monitoring. For example, periodic monitoring is performed to detect any change over time in the impurity level of fluid in chamber 11 or chamber 111. If, during the performance of periodic monitoring, deposits are detected, bubbles form at too low of voltage, or bubbles persist after voltage is removed, the initial cleaning and testing can be performed again.